WHITE ELECTRONIC DESIGNS

WED2ZL64512S

512K x 64 Synchronous Pipeline NBL SRAM

FEATURES

- Fast clock speed: 166, 150, 133, and 100MHz
- Fast access times: 3.5ns, 3.8ns, 4.2ns, and 5.0ns
- Fast OE# access times: 3.5ns, 3.8ns, 4.2ns, and 5.0ns
- Seperate +2.5V ± 5% power supplys for core I/O (V_{CC} + V_{CCQ})
- Double Word Write Control
- Clock-controlled and registered addresses, data I/Os and control signals
- Packaging:
  - 119 bump BGA package
- Low capacitive bus loading

DESCRIPTION

The WEDC SyncBurst - SRAM family employs high-speed, low-power CMOS designs that are fabricated using an advanced CMOS process. WEDC's 32Mb Sync SRAM integrate two 512K x 32 SRAMs into a single BGA package to provide 512K x 64 configuration. All synchronous inputs pass through registers controlled by a positive-edge-triggered single-clock input (CK). The NBL or No Bus Latency Memory utilizes all the bandwidth in any combination of operating cycles. Address, data inputs, and all control signals except output enable are synchronized to input clock. Output Enable controls the outputs at any given time and to Asynchronous Input. Write cycles are internally self-timed and initiated by the rising edge of the clock input. This feature eliminates complex off-chip write pulse generation and provides increased timing flexibility for incoming signals.

NOTE: NBL = No Bus Latency is equivalent to the industry ZBT™ devices.

FIG. 1 PIN CONFIGURATION

(TOP VIEW)

	1	2	3	4	5	6	7	8	9
A	DQ_F	DQ_F	DQ_F	DQ_F	NC	DQ_G	DQ_G	DQ_G	DQ_G
B	DQ_F	DQ_F	DQ_F	DQ_F	NC	DQ_G	DQ_G	DQ_G	DQ_G
C	DQ_E	DQ_E	DQ_E	DQ_E	NC	DQ_H	DQ_H	DQ_H	DQ_H
D	DQ_E	DQ_E	DQ_E	DQ_E	NC	DQ_H	DQ_H	DQ_H	DQ_H
E	NC	NC	NC	V_{CCQ}	V_{CCQ}	V_{CCQ}	NC	NC	NC
F	SA	V_{CCQ}	V_{CC}	V_{CC}	V_{CC}	V_{CC}	V_{CC}	V_{CCQ}	SA
G	SA	CE#	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	SA	SA
H	SA	NC	V_{SS}	WE_1#	V_{SS}	V_{SS}	V_{SS}	SA	SA
J	SA_{18}	CE_2#	SS_{CK}	OE#	NC	NC	NC	SA_1	SA_0
K	SA	CE_2	V_{SS}	WE_0#	V_{SS}	V_{SS}	V_{SS}	SA	SA
L	SA	NC	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	SA	SA
M	SA	V_{CCQ}	V_{CC}	V_{CC}	V_{CC}	V_{CC}	V_{CC}	V_{CCQ}	SA
N	NC	NC	NC	V_{CCQ}	V_{CCQ}	V_{CCQ}	NC	NC	NC
P	DQ_D	DQ_D	DQ_D	DQ_D	NC	DQ_A	DQ_A	DQ_A	DQ_A
R	DQ_D	DQ_D	DQ_D	DQ_D	NC	DQ_A	DQ_A	DQ_A	DQ_A
T	DQ_C	DQ_C	DQ_C	DQ_C	NC	DQ_B	DQ_B	DQ_B	DQ_B
U	DQ_C	DQ_C	DQ_C	DQ_C	NC	DQ_B	DQ_B	DQ_B	DQ_B

BLOCK DIAGRAM
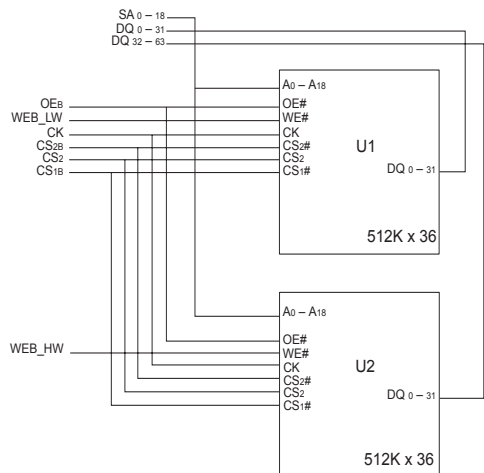
FUNCTION DESCRIPTION

The WED2ZL64512S is an NBL SSRAM designed to sustain 100% bus bandwidth by eliminating turnaround cycle when there is transition from Read to Write, or vice versa. All inputs (with the exception of OE#) are synchronized to rising clock edges.

Output Enable (OE#) can be used to disable the output at any given time. Read operation is initiated when at the rising edge of the clock, the address presented to the address inputs are latched in the address register, CKE# is driven low, the write enable input signals WE# are driven high. The internal array is read between the first rising edge and the second rising edge of the clock and the data is latched in the output register. At the second clock edge the data is driven out of the SRAM. During read operation OE# must be driven low for the device to drive out the requested data.

Write operation occurs when WE# is driven low at the rising edge of the clock. The pipe-lined NBL SSRAM uses a late-late write cycle to utilize 100% of the bandwidth. At the first rising edge of the clock, WE# and address are registered, and the data associated with that address is required two cycle later.

TRUTH TABLES

SYNCHRONOUS TRUTH TABLE

CEx#	WE#	OE#	CK	Address Accessed	Operation
H	X	X	↑	N/A	Deselect
L	H	L	↑	Current Address	Read Cycle
L	H	H	↑	N/A	NOP/Dummy Read
X	X	H	↑	N/A	Dummy Read
L	L	X	↑	Current Address	Write Cycle
L	L	X	↑	N/A	NOP/Write Abort

NOTES:
1. X means "Don't Care."
2. The rising edge of clock is symbolized by (↑)
3. A continue deselect cycle can only be entered if a deselect cycle is executed first.
4. WRITE# = L means Write operation in WRITE TRUTH TABLE.
   WRITE# = H means Read operation in WRITE TRUTH TABLE.

ABSOLUTE MAXIMUM RATINGS*

Voltage on V_{CC} Supply Relative to Vss	$-0.3V \leq T_A \leq +3.6V$
V_{IN} (DQx)	$-0.3V \leq T_A \leq +3.6V$
V_{IN} (Inputs)	$-0.3V \leq T_A \leq +3.6V$
Storage Temperature (BGA)	$-55°C \leq T_A \leq +125°C$
Short Circuit Output Current	100mA

*Stress greater than those listed under "Absolute Maximum Ratings: may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions greater than those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating condtions for extended periods may affect reliability.

ELECTRICAL CHARACTERISTICS ($0°C \leq T_A \leq 70°C$)

Description	Symbol	Conditions	Min	Max	Units	Notes
Input High (Logic 1) Voltage	V_{IH}		1.7	V_{CC} +0.3	V	1
Input Low (Logic 0) Voltage	V_{IL}		-0.3	0.7	V	1
Input Leakage Current	I_{LI}	0V V_{IN} V_{CC}	-5	5	mA	
Output Leakage Current	I_{LO}	Output(s) Disabled, 0V V_{IN} V_{CC}	-5	5	mA	
Output High Voltage	V_{OH}	I_{OH} = -1.0mA	2.0	---	V	1
Output Low Voltage	V_{OL}	I_{OL} = 1.0mA	---	0.4	V	1
Supply Voltage	V_{CC}		2.375	2.625	V	1

NOTES: 1. All voltages referenced to V_{SS} (GND)

DC CHARACTERISTICS

Description	Symbol	Conditions	Typ	166 MHz	150 MHz	133 MHz	100 MHz	Units	Notes
Power Supply Current: Operating	I_{CC}	Device Selected; All Inputs $\leq V_{IL}$ or $\geq V_{IH}$; Cycle Time = T_{CYC} MIN; V_{CC} = MAX; Output Open		650	600	560	500	mA	1, 2
Power Supply Current: Standby	I_{SB2}	Device Deselected; V_{CC} = MAX; All Inputs $\leq V_{SS}$ + 0.2 or V_{CC} - 0.2; All Inputs Static; CK Frequency = 0	30	60	60	60	60	mA	2
Clock Running Standby Current	I_{SB4}	Device Deselected; V_{CC} = MAX; All Inputs $\leq V_{SS}$ + 0.2 or V_{CC} - 0.2; Cycle Time = T_{CYC} MIN		140	120	100	80	mA	2

NOTES: 1. I_{CC} is specified with no output current and increases with faster cycle times. I_{CC} increases with faster cycle times and greater output loading.
2. Typical values are measured at 2.5V, 25°C, and 10ns cycle time.

BGA CAPACITANCE

Description	Symbol	Conditions	Typ	Max	Units	Notes
Control Input Capacitance	C_L	T_A = 25°C; f = 1MHz	5	7	pF	1
Input/Output Capacitance (DQ)	C_O	T_A = 25°C; f = 1MHz	6	8	pF	1
Address Capacitance	C_A	T_A = 25°C; f = 1MHz	5	7	pF	1
Clock Capacitance	C_{CK}	T_A = 25°C; f = 1MHz	3	5	pF	1

NOTES: 1. This parameter is sampled.

AC CHARACTERISTICS

| Parameter	Symbol	166MHz Min	166MHz Max	150MHz Min	150MHz Max	133MHz Min	133MHz Max	100MHz Min	100MHz Max	Units
Clock Time	t_{CYC}	6.0		6.7		7.5		10.0		ns
Clock Access Time	t_{CD}	--	3.5	--	3.8	--	4.2	--	5.0	ns
Output enable to Data Valid	t_{OE}	--	3.5	--	3.8	--	4.2	--	5.0	ns
Clock High to Output Low-Z	t_{LZC}	1.5	--	1.5	--	1.5	--	1.5	--	ns
Output Hold from Clock High	t_{OH}	1.5	--	1.5	--	1.5	--	1.5	--	ns
Output Enable Low to output Low-Z	t_{LZOE}	0.0	--	0.0	--	0.0	--	0.0	--	ns
Output Enable High to Output High-Z	t_{HZOE}	--	3.0	--	3.0	--	3.5	--	3.5	ns
Clock High to Output High-Z	t_{HZC}	--	3.0	--	3.0	--	3.5	--	3.5	ns
Clock High Pulse Width	t_{CH}	2.2	--	2.5	--	3.0	--	3.0	--	ns
Clock Low Pulse Width	t_{CL}	2.2	--	2.5	--	3.0	--	3.0	--	ns
Address Setup to Clock High	t_{AS}	1.5	--	1.5	--	1.5	--	1.5	--	ns
CKE Setup to Clock High	t_{CES}	1.5	--	1.5	--	1.5	--	1.5	--	ns
Data Setup to Clock High	t_{DS}	1.5	--	1.5	--	1.5	--	1.5	--	ns
Write Setup to Clock High	t_{WS}	1.5	--	1.5	--	1.5	--	1.5	--	ns
Chip Select Setup to Clock High	t_{CSS}	1.5		1.5		1.5		1.5		ns
Address Hold to Clock high	t_{AH}	0.5	--	0.5	--	0.5	--	0.5	--	ns
CKE Hold to Clock High	t_{CEH}	0.5	--	0.5	--	0.5	--	0.5	--	ns
Data Hold to Clock High	t_{DH}	0.5	--	0.5	--	0.5	--	0.5	--	ns
Write Hold to Clock High	t_{WH}	0.5	--	0.5	--	0.5	--	0.5	--	ns
Chip Select Hold to Clock High	t_{CSH}	0.5	--	0.5	--	0.5	--	0.5	--	ns

NOTES:
1. All Address inputs must meet the specified setup and hold times for all rising clock (CK) edges when ADV is sampled low and CE$_X$# is sampled valid.
   All other synchronous inputs must meet the specified setup and hold times whenever this device is chip selected.
2. Chip enable must be valid at each rising edge of CK (when ADV is Low) to remain enabled.
3. A write cycle is defined by WE# low having been registered into the device. A Read cycle is defined by WE# High.
   Both cases must meet setup and hold times.

AC TEST CONDITIONS
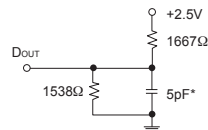(0°C ≤ T$_A$≤ 70°C, V$_{CC}$ = 2.5V ± 5%, Unless Otherwise Specified)

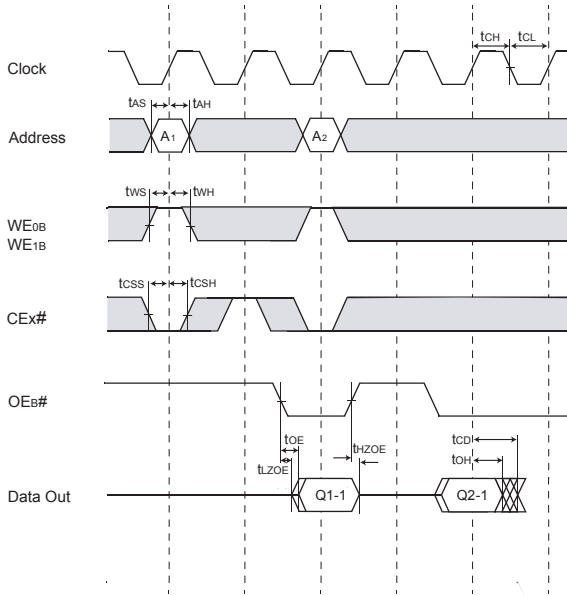| Parameter	Value
Input Pulse Level	0 to 2.5V
Input Rise and Fall Time (Measured at 20% to 80%)	1.0V/ns
Input and Output Timing Reference Levels	1.25V
Output Load	See Output Load (A)

OUTPUT LOAD (A)
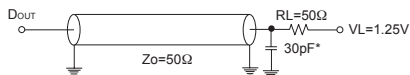
OUTPUT LOAD (B)
(FOR t_{LZC}, t_{LZOE}, t_{HZOE}, and t_{HZC})

Including Scope and Jig Capacitance

FIG. 3 TIMING WAVEFORM OF READ CYCLE

Clock
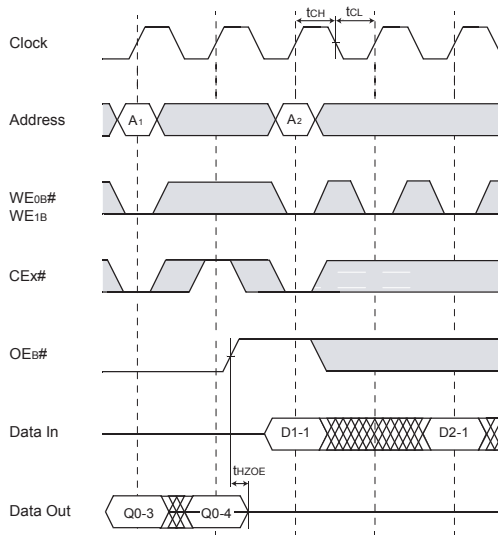
Address

WE0B
WE1B

CEx#

OEB#

Data Out

NOTES: WRITE# = L means WE# = L, and BWx# = L
CEx# refers to the combination of CE1#, CE2, CE2#.

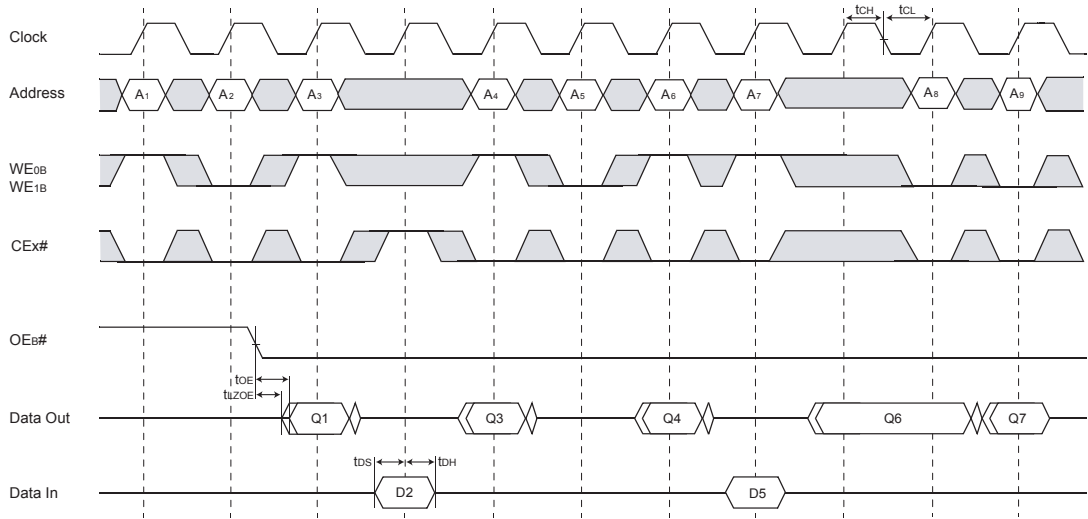☐ Don't Care
▨ Undefined

FIG. 4   **TIMING WAVEFORM OF WRITE CYCLE**

NOTES: WRITE# = L means WE# = L, and BWx# = L
CEx# refers to the combination of CE1#, CE2 and CE2#.

☐ Don't Care
▨ Undefined
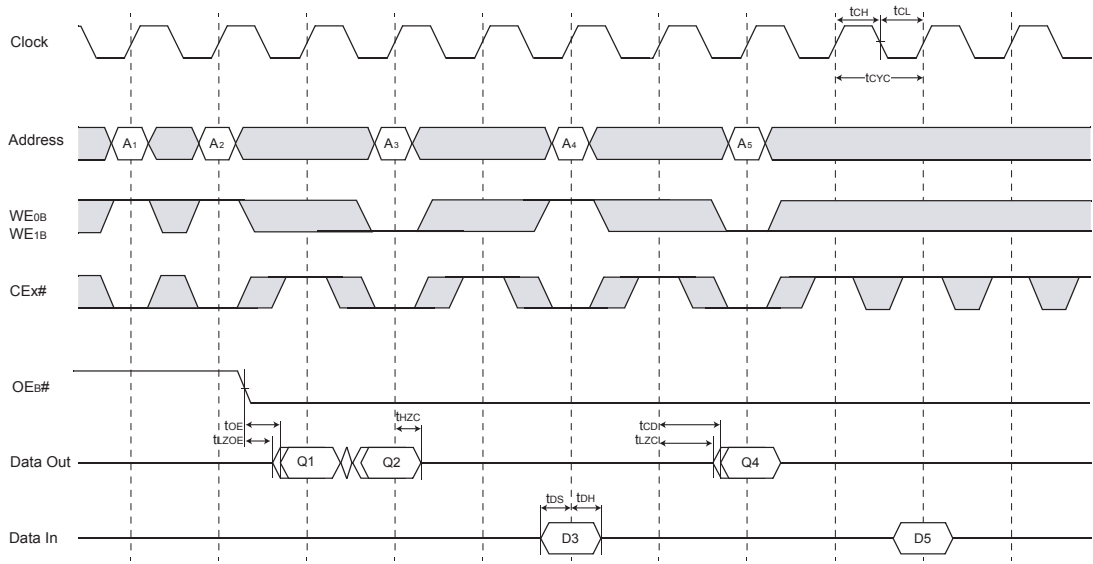
FIG. 5 TIMING WAVEFORM OF SINGLE READ/WRITE

NOTES: WRITE# = L means WE# = L, and BWx# = L
         CEx# refers to the combination of CE₁#, CE₂ and CE₂#.

□ Don't Care
▨ Undefined

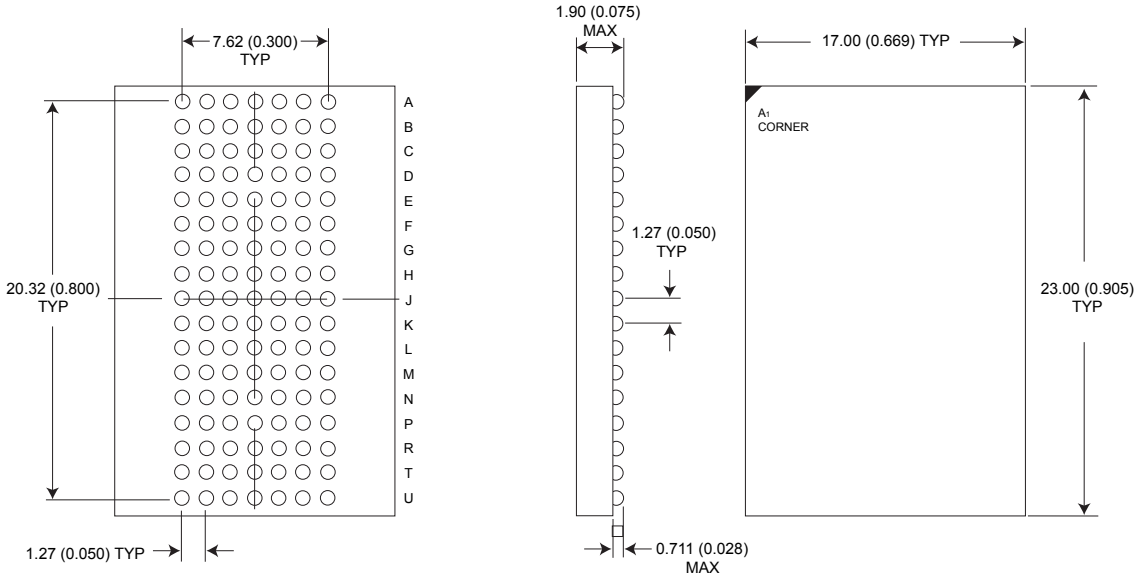## FIG. 7   TIMING WAVEFORM OF CE# OPERATION

NOTES: WRITE# = L means WE# = L, and BWx# = L
CEx# refers to the combination of CE1#, CE2 and CE2#.

☐ Don't Care
☒ Undefined

PACKAGE DIMENSION: 119 BUMP PBGA

7.62 (0.300) TYP

1.90 (0.075) MAX

17.00 (0.669) TYP

A₁ CORNER

20.32 (0.800) TYP

1.27 (0.050) TYP

23.00 (0.905) TYP

A
B
C
D
E
F
G
H
J
K
L
M
N
P
R
T
U

1.27 (0.050) TYP

0.711 (0.028) MAX

ALL LINEAR DIMENSIONS ARE IN MILLIMETERS AND PARENTHETICALLY IN INCHES

NOTE: Ball attach pad for above BGA package is 620 microns in diameter. Pad is solder mask defined.

ORDERING INFORMATION

COMMERCIAL TEMP RANGE (0°C ≤ TA ≤ 70°C)

Part Number	Configuration	t_{CD} (ns)	Clock (MHz)
WED2ZL64512S35BC	512K x 64	3.5	166
WED2ZL64512S38BC	512K x 64	3.8	150
WED2ZL64512S42BC	512K x 64	4.2	133
WED2ZL64512S50BC	512K x 64	5.0	100